

Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 117613		APPLICATION NO. New US Application	
INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)				APPLICANTS Osamu FUKAWATASE et al.			
				FILING DATE October 28, 2003			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	
<i>FWF</i>	1	JP B2 2679405 (with abstract)	08/01/1997	Japan			
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
EXAMINER	<i>John M. Flinn</i>				DATE CONSIDERED <i>08/21/04</i>		
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: October 28, 2003

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ATTY DOCKET NO.  
117613

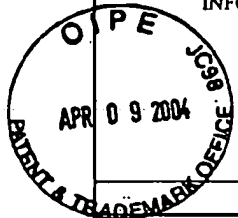
APPLICATION NO.  
10/693,991

INFORMATION DISCLOSURE STATEMENT

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Osamu FUKAWATASE et al.

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DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS
1 JP 58056945 (abstract only)	04/04/1983	Japan		
2 DE 299 06 887 U 1	10/14/1999	Germany		
3 WO 01/68409 A1	09/20/2001	WIPO		
4 WO 01/36983 A2	05/25/2001	WIPO		
5 EP 0 421 572 A2	04/10/1991	Europe		

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)


EXAMINER

*Paul W. Flannery*

DATE CONSIDERED

*08/21/04*

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